# GP1S94J0000F

Gap : 3.5mm Slit : 0.3mm Phototransistor Output, **Compact Transmissive Photointerrupter** 



# Description

GP1S94J0000F is a compact-package, phototransistor output, transmissive photointerrupter, with opposing emitter and detector in a molding that provides non-contact sensing. The compact package series is a result of unique technology combing transfer and injection molding.

This device has a wide gap and positioning pins.

#### Features

- 1. Transmissive with phototransistor output
- 2. Highlights:
  - Compact Size
  - 2 Positioning Pins of unequal size to prevent misalignment
- 3. Key Parameters:
  - · Gap Width : 3.5mm
  - Slit Width (detector side): 0.3mm
  - Package : 6×3.4×5.2mm
- 4. Lead free and RoHS directive compliant

# ■ Agency approvals/Compliance

1. Compliant with RoHS directive

#### Applications

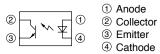
- 1. General purpose detection of object presence or motion.
- 2. Example : printer, lens control for camera

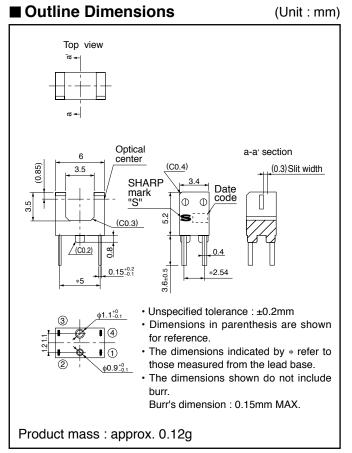
Notice The content of data sheet is subject to change without prior notice. In the absence of confirmation by device specification sheets, SHARP takes no responsibility for any defects that may occur in equipment using any SHARP devices shown in catalogs, data books, etc. Contact SHARP in order to obtain the latest device specification sheets before using any SHARP device.



#### ■ Internal Connection Diagram

Top view





Plating material : SnCu (Cu : TYP. 2%)

# SHARP

# Date code (2 digit)

iait			
1st digit		2nd digit	
Year of production		Month of production	
Mark	Month	Mark	
0	1	1	
1	2	2	
2	3	3	
3	4	4	
4	5	5	
5	6	6	
6	7	7	
7	8	8	
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0	11	Y	
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	oduction           Mark           0           1           2           3           4           5           6           7           8           9	oduction         Month of p           Mark         Month           0         1           1         2           2         3           3         4           4         5           5         6           6         7           7         8           8         9           9         10           0         11	

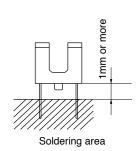
repeats in a 10 year cycle

# Rank mark

There is no rank indicator.

Country of origin Japan SHARP

Absolute Maximum Ratings (T <sub>a</sub>			T <sub>a</sub> =25°C)	
Parameter		Symbol	Rating	Unit
	Forward current	I <sub>F</sub>	50	mA
Input	Reverse voltage	V <sub>R</sub>	6	V
	Power dissipation	Р	75	mW
	Collector-emitter voltage	V <sub>CEO</sub>	35	V
Output	Emitter-collector voltage	V <sub>ECO</sub>	6	V
Output	Collector current	I <sub>C</sub>	20	mA
	Collector power dissipation	P <sub>C</sub>	75	mW
Total	power dissipation	P <sub>tot</sub>	100	mW
Opera	ting temperature	T <sub>opr</sub>	-25 to +85	°C
Storag	ge temperature	T <sub>stg</sub>	-40 to +100	°C
*1Solder	ring temperature	T <sub>sol</sub>	260	°C



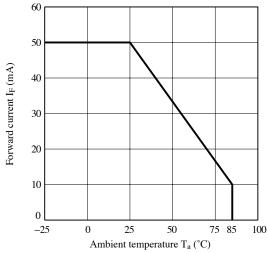
\*1 For 5s or less

# Electro-optical Characteristics

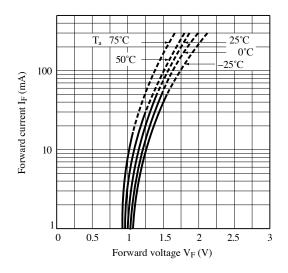
 $(T_a=25^{\circ}C)$ Symbol MIN. TYP. MAX. Parameter Condition Unit I<sub>F</sub>=20mA Forward voltage  $V_{\rm F}$ \_ 1.2 1.4 V Input  $V_R=3V$ Reverse current  $I_R$ 10 μΑ \_ \_ Output Collector dark current  $V_{CE}=20V$ 100 nA I<sub>CEO</sub> \_ \_ 400 Collector current  $V_{CE}=5V, I_F=5mA$  $I_{\rm C}$ 40 μΑ \_ Transfer Collector-emitter saturation voltage  $I_F=10mA$ ,  $I_C=40\mu A$ 0.4 V V<sub>CE(sat)</sub> \_ \_ charac-150 Rise time 50 \_  $\mathbf{t}_{\mathrm{r}}$ μs Response time  $V_{CE}$ =5V,  $I_C$ =100 $\mu$ A,  $R_L$ =1 $k\Omega$ teristics Fall time  $t_{\mathrm{f}}$ 50 150 μs \_

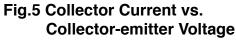






# Fig.3 Forward Current vs. Forward Voltage





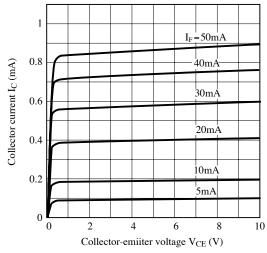
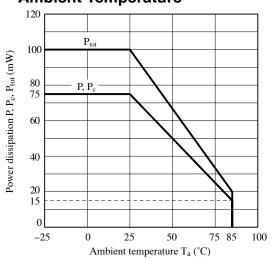
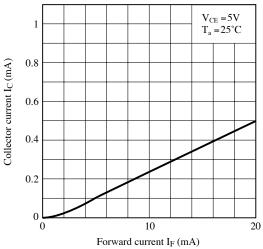


Fig.2 Power Dissipation vs. Ambient Temperature









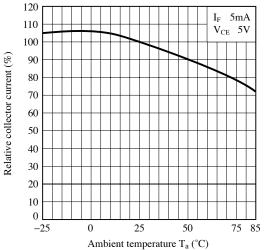
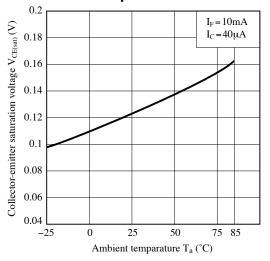
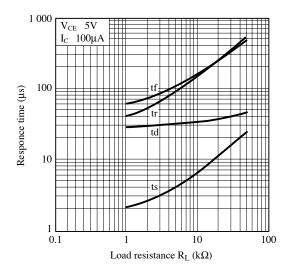




Fig.7 Collector-emitter Saturation Voltage vs. Ambient Temperature



# Fig.9 Response Time vs. Load Resistance





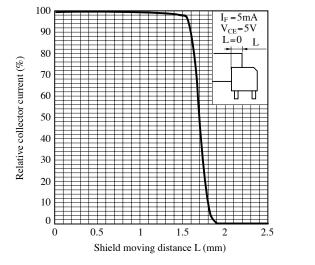
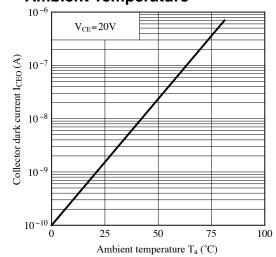
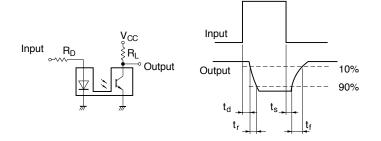


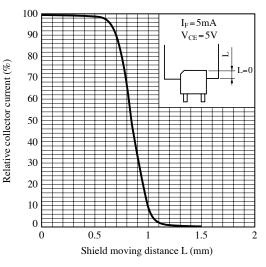
Fig.8 Collector dark Current vs. Ambient Temperature

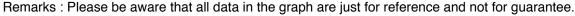


# Fig.10 Test Circuit for Response Time











## Design Considerations

#### Design guide

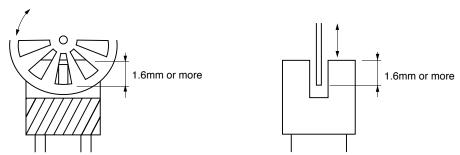
1) Prevention of detection error

To prevent photointerrupter from faulty operation caused by external light, do not set the detecting face to the external light.

2) Position of opaque board

Opaque board shall be installed at place 1.6mm or more from the top of elements.





This product is not designed against irradiation and incorporates non-coherent IRED.

## Degradation

In general, the emission of the IRED used in photointerrupter will degrade over time.

In the case of long term operation, please take the general IRED degradation (50% degradation over 5 years) into the design consideration.

#### Parts

This product is assembled using the below parts.

# • Photodetector (qty. : 1)

Category	Material	Maximum Sensitivity wavelength (nm)	Sensitivity wavelength (nm)	Response time (µs)
Phototransistor	Silicon (Si)	930	700 to 1 200	20

#### • Photo emitter (qty. : 1)

Category	Material	Maximum light emitting wavelength (nm)	I/O Frequency (MHz)
Infrared emitting diode (non-coherent)	Gallium arsenide (GaAs)	950	0.3

#### Material

Case	Lead frame	Lead frame plating
Black polyphernylene sulfide resin (UL94 V-0)	42Alloy	SnCu plating



#### Manufacturing Guidelines

#### Soldering Method

Flow Soldering:

Soldering should be completed below 260°C and within 5 s.

Please solder within one time.

Soldering area is 1mm or more away from the bottom of housing.

Please take care not to let any external force exert on lead pins.

Please don't do soldering with preheating, and please don't do soldering by reflow.

#### Hand soldering

Hand soldering should be completed within 3 s when the point of solder iron is below 350°C. Please solder within one time.

Please don't touch the terminals directly by soldering iron.

Soldered product shall treat at normal temperature.

#### Other notice

Please test the soldering method in actual condition and make sure the soldering works fine, since the impact on the junction between the device and PCB varies depending on the cooling and soldering conditions.

#### Cleaning instructions

#### Solvent cleaning :

Solvent temperature should be 45°C or below. Immersion time should be 3 minutes or less.

Ultrasonic cleaning :

Do not execute ultrasonic cleaning.

#### Recommended solvent materials :

Ethyl alcohol, Methyl alcohol and Isopropyl alcohol.

#### Presence of ODC

This product shall not contain the following materials. And they are not used in the production process for this product. Regulation substances : CFCs, Halon, Carbon tetrachloride, 1.1.1-Trichloroethane (Methylchloroform)

Specific brominated flame retardants such as the PBBOs and PBBs are not used in this product at all.

This product shall not contain the following materials banned in the RoHS Directive (2002/95/EC).
Lead, Mercury, Cadmium, Hexavalent chromium, Polybrominated biphenyls (PBB), Polybrominated diphenyl ethers (PBDE).



## ■ Package specification

# Sleeve package

Package materials Sleeve : Polystyrene Stopper : Styrene-Butadiene

Package method

MAX. 50 pcs. of products shall be packaged in a sleeve. Both ends shall be closed by tabbed and tabless stoppers.

MAX. 50 sleeves in one case.

# SHARP

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- --- Office automation equipment
- --- Telecommunication equipment [terminal]
- --- Test and measurement equipment
- --- Industrial control
- --- Audio visual equipment
- --- Consumer electronics

(ii) Measures such as fail-safe function and redundant design should be taken to ensure reliability and safety when SHARP devices are used for or in connection with equipment that requires higher reliability such as:

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- --- Traffic signals
- --- Gas leakage sensor breakers
- --- Alarm equipment
- --- Various safety devices, etc.

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- --- Telecommunication equipment [trunk lines]
- --- Nuclear power control equipment
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